REMARKS

Applicant respectfully requests that the Examiner consider the claims and the replacements proposed.

No new matter has been added, merely amended to more particularly point out and distinctly claim the subject matter Applicant believes is inventive. Applicant respectfully submits that the Claims as they now stand are patentably distinct over the allowed Claims of the parent application and the art cited during the prosecution thereof.

Applicant believes additional fees in the amount of $108.00 for 6 Independent Claims are due as attached to the enclosed PTO/SB/017 Fee Transmittal Sheet. However, the Commissioner also is hereby authorized to charge any fees or credit any overpayment to Deposit Account Number 23-2426 of WINSTEAD SECHREST & MINICK P.C.

If the Examiner has any questions or comments concerning this paper or the present application in general, the Examiner is invited to call the undersigned at (214) 745-5374.

Respectfully submitted,
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ATTACHMENT A

This Attachment A indicates all Changes the text. Changes are indicated with insertions of new text underlined and deletions of old text bracketed:

21. The method of Claim 7 wherein:

said step of observing parameters at a plurality of test nodes comprises the step of observing n number of parameters; and

said step of selectively stepping the level of the supply current in response to a number of errors detected comprises the step of stepping the level of the supply current by one of 2n number of steps for n number of parameters.

22. The method of Claim 7 wherein said second time interval is divided into a plurality of sub-intervals and said step of stepping the level of the supply current comprises the substeps of:

during a first sub-interval selectively stepping the level of the supply current in response to at least one error detected; and

during a second sub-interval selectively stepping the level of the supply current in response to at least one error detected.

23. The method of Claim 7 wherein said step of initiating a test mode comprises the substeps of:

monitoring a power supply voltage; and

initiating the test mode when the power supply voltage crosses a preselected threshold.

24. The method of Claim 7 wherein said step of initiating a test mode comprises the substep of initiating a state machine for generating a plurality of timing signals defining the first and second time intervals.

25. The method of Claim 7 wherein said step of initiating a test mode comprises the substep of applying a voltage to a selected terminal of the integrated circuit.

26. The method of Claim 7 wherein said step of initiating a test mode comprises the substeps of:

connecting an input pin of the integrated circuit to a selected voltage; and

comparing the voltage at the input pin against a threshold.

27. A method of testing an integrated circuit including a plurality of test nodes comprising the steps of:

initiating a test mode;

observing parameters at the plurality of test nodes to detect errors;

selectively modulating a power supply current to the integrated circuit in response to a number of errors detected; and

decoding the modulated power supply current to identify the detected errors.

28. The method of Claim 27 wherein said step of modulating comprises the step of pulse-width modulating the power supply current.

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